## NX3008PBK

# 30 V, 230 mA P-channel Trench MOSFET Rev. 1 — 1 August 2011

**Product data sheet** 

## **Product profile**

#### 1.1 General description

P-channel enhancement mode Field-Effect Transistor (FET) in a small SOT23 (TO-236AB) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

#### 1.2 Features and benefits

- Very fast switching
- Low threshold voltage
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

### 1.3 Applications

- Relay driver
- High-speed line driver

- High-side loadswitch
- Switching circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> = 25 °C	-	-	-30	V
$V_{GS}$	gate-source voltage		-8	-	8	V
I <sub>D</sub>	drain current	$V_{GS} = -4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	[1]	-	-230	mΑ
Static cha	racteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = -4.5 \text{ V};$ $I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$	-	2.8	4.1	Ω

<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



30 V, 230 mA P-channel Trench MOSFET

## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	S	source	3	D
3	D	drain	1	S 017aaa259

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
NX3008PBK	TO-236AB	plastic surface-mounted package; 3 leads	SOT23

## 4. Marking

Table 4. Marking codes

Type number	Marking code <sup>[1]</sup>
NX3008PBK	KT%

<sup>[1] % =</sup> placeholder for manufacturing site code.

30 V, 230 mA P-channel Trench MOSFET

## 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> = 25 °C	-	-30	V
V <sub>GS</sub>	gate-source voltage		-8	8	V
I <sub>D</sub>	drain current	$V_{GS} = -4.5 \text{ V}; T_{amb} = 25 ^{\circ}\text{C}$	<u>[1]</u> _	-230	mA
		V <sub>GS</sub> = -4.5 V; T <sub>amb</sub> = 100 °C	<u>[1]</u> _	-145	mA
I <sub>DM</sub>	peak drain current	$T_{amb} = 25$ °C; single pulse; $t_p \le 10 \mu s$	-	-1	Α
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = 25 °C	[2] _	350	mW
			<u>[1]</u> _	420	mW
		T <sub>sp</sub> = 25 °C	-	1140	mW
Tj	junction temperature		-55	150	°C
T <sub>amb</sub>	ambient temperature		-55	150	°C
T <sub>stg</sub>	storage temperature		-65	150	°C
Source-drai	in diode				
Is	source current	T <sub>amb</sub> = 25 °C	<u>[1]</u> _	-230	mA
ESD maxim	um rating				
V <sub>ESD</sub>	electrostatic discharge voltage	HBM	[3]	2000	V

 $<sup>\</sup>label{eq:condition} \textbf{[1]} \quad \text{Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm$^2$.}$ 

<sup>[2]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

<sup>[3]</sup> Measured between all pins.

#### 30 V, 230 mA P-channel Trench MOSFET

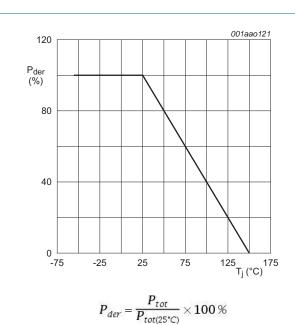


Fig 1. Normalized total power dissipation as a function of junction temperature

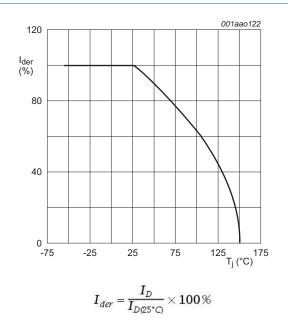
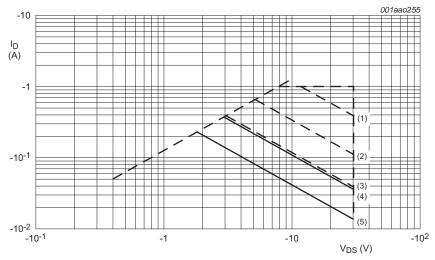


Fig 2. Normalized continuous drain current as a function of junction temperature



I<sub>DM</sub> is a single pulse

- (1)  $t_p = 1 \text{ ms}$
- (2)  $t_p = 10 \text{ ms}$
- (3)  $t_p = 100 \text{ ms}$
- (4) DC;  $T_{sp} = 25 \, ^{\circ}\text{C}$
- (5) DC;  $T_{amb} = 25 \text{ °C}$ ; 1 cm<sup>2</sup> drain mounting pad

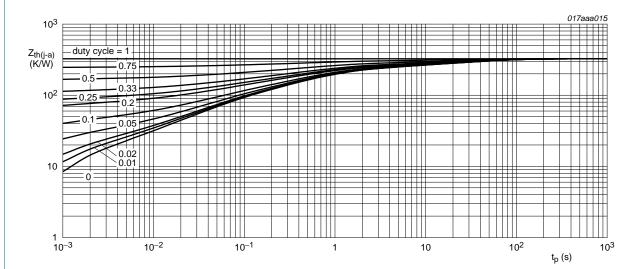
Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

## 6. Thermal characteristics

Table 6. Thermal characteristics

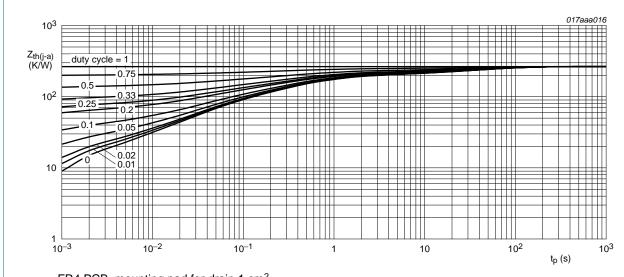
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> _	310	370	K/W
			[2] _	260	300	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	115	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



FR4 PCB, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm<sup>2</sup>

Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 30 V, 230 mA P-channel Trench MOSFET

## 7. Characteristics

Table 7. Characteristics

B					
Parameter	Conditions	Min	Тур	Max	Unit
racteristics					
drain-source breakdown voltage	$I_D = -250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	-30	-	-	V
gate-source threshold voltage	$I_D = -250 \ \mu A; \ V_{DS} = V_{GS}; \ T_j = 25 \ ^{\circ}C$	-0.6	-0.9	-1.1	V
drain leakage current	$V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	-10	μΑ
	$V_{DS} = -30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	-1	μΑ
gate leakage current	$V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-0.2	-1	μΑ
	$V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-0.2	-1	μA
	$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-10	-	nΑ
	$V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-10	-	nΑ
	$V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-1	-	nΑ
	$V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-1	-	nΑ
drain-source on-state resistance	$V_{GS} = -4.5 \text{ V}; I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$	-	2.8	4.1	Ω
	$V_{GS} = -4.5 \text{ V}; I_D = -200 \text{ mA}; T_j = 150 ^{\circ}\text{C}$	-	5.3	7.8	Ω
	$V_{GS} = -2.5 \text{ V}; I_D = -10 \text{ mA}; T_j = 25 \text{ °C}$	-	5.3	6.5	Ω
forward transconductance	$V_{DS} = -10 \text{ V}; I_D = -200 \text{ mA}; T_j = 25 \text{ °C}$	-	160	-	mS
characteristics					
total gate charge	$V_{DS} = -15 \text{ V}; I_D = -200 \text{ mA};$	-	0.55	0.72	nC
gate-source charge	$V_{GS} = -4.5 \text{ V}; T_j = 25 \text{ °C}$	-	0.23	-	nC
gate-drain charge		-	0.09	-	nC
input capacitance	$V_{DS} = -15 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$	-	31	46	pF
output capacitance	T <sub>j</sub> = 25 °C	-	6.5	-	pF
reverse transfer capacitance		-	2.3	-	pF
turn-on delay time	$V_{DS} = -20 \text{ V}; R_L = 250 \Omega; V_{GS} = -4.5 \text{ V};$	-	19	38	ns
rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	30	-	ns
turn-off delay time		-	65	130	ns
fall time		-	38	-	ns
ain diode					
source-drain voltage	$I_S = -200 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-0.47	-0.88	-1.2	٧
	drain-source threshold voltage drain leakage current  gate leakage current  drain-source on-state resistance  forward transconductance characteristics total gate charge gate-source charge gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time rise time turn-off delay time fall time	$ \begin{array}{c} \text{drain-source} \\ \text{breakdown voltage} \\ \text{gate-source threshold} \\ \text{voltage} \\ \text{drain leakage current} \\ \text{V}_{DS} = -250~\mu\text{A}; \ V_{DS} = V_{GS}; \ T_j = 25~\text{°C} \\ \text{V}_{DS} = -30~\text{V}; \ V_{GS} = 0~\text{V}; \ T_j = 150~\text{°C} \\ \text{V}_{DS} = -30~\text{V}; \ V_{GS} = 0~\text{V}; \ T_j = 25~\text{°C} \\ \text{V}_{DS} = -30~\text{V}; \ V_{DS} = 0~\text{V}; \ T_j = 25~\text{°C} \\ \text{V}_{GS} = 8~\text{V}; \ V_{DS} = 0~\text{V}; \ T_j = 25~\text{°C} \\ \text{V}_{GS} = 8~\text{V}; \ V_{DS} = 0~\text{V}; \ T_j = 25~\text{°C} \\ \text{V}_{GS} = 4.5~\text{V}; \ V_{DS} = 0~\text{V}; \ T_j = 25~\text{°C} \\ \text{V}_{GS} = -4.5~\text{V}; 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\ T_j = 25~$	$ \begin{array}{c} \mbox{drain-source} \\ \mbox{breakdown voltage} \\ \mbox{gate-source threshold voltage} \\ \mbox{gate-source threshold voltage} \\ \mbox{drain leakage current} \\ \mbox{V}_{DS} = -30 \ V; \ V_{OS} = 0 \ V; \ T_j = 150 \ ^{\circ} \mbox{C} \\ \mbox{V}_{DS} = -30 \ V; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{DS} = -30 \ V; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -8 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -8 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -4.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -4.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -2.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -2.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -2.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -2.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -2.5 \ V; \ V_{DS} = 0 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -4.5 \ V; \ I_D = -200 \ mA; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{V}_{OS} = -4.5 \ V; \ I_D = -200 \ mA; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{C} \\ \mbox{Total gate charge} \\ \mbox{V}_{DS} = -10 \ V; \ I_D = -200 \ mA; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{C} \\ \mbox{Staracteristics} \\ \mbox{total gate charge} \\ \mbox{V}_{OS} = -4.5 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{Staracteristics} \\ \mbox{Total gate charge} \\ \mbox{V}_{DS} = -15 \ V; \ I_D = -200 \ mA; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{C} \\ \mbox{Staracteristics} \\ \mbox{Total gate charge} \\ \mbox{V}_{DS} = -15 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{C} \\ \mbox{C} \\ \mbox{Staracteristics} \\ \mbox{Total gate charge} \\ \mbox{V}_{DS} = -20 \ V; \ T_j = 25 \ ^{\circ} \mbox{C} \\ \mbox{C} \\$		$ \begin{array}{c} drain\text{-source} \\ breakdown voltage \\ gate-source threshold voltage \\ \\ gate-source threshold voltage \\ \\ drain leakage current \\ \\ V_{DS} = -30 \text{ V}; V_{QS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{DS} = -30 \text{ V}; V_{QS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C} \\ V_{DS} = -30 \text{ V}; V_{QS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{DS} = -30 \text{ V}; V_{QS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C} \\ V_{QS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; 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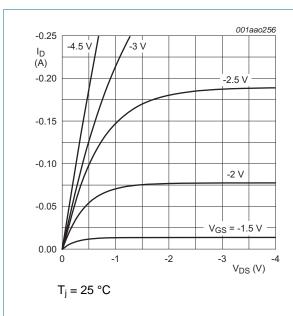
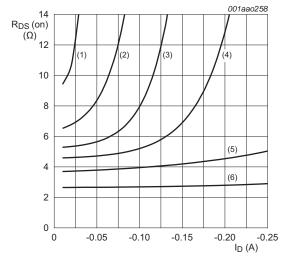


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



T<sub>i</sub> = 25 °C

(1)  $V_{GS} = -1.75 \text{ V}$ 

(2)  $V_{GS} = -2.0 \text{ V}$ 

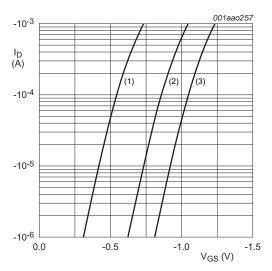
(3)  $V_{GS} = -2.25 \text{ V}$ 

(4)  $V_{GS} = -2.5 \text{ V}$ 

(5)  $V_{GS} = -3.0 \text{ V}$ 

(6)  $V_{GS} = -4.5 \text{ V}$ 

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



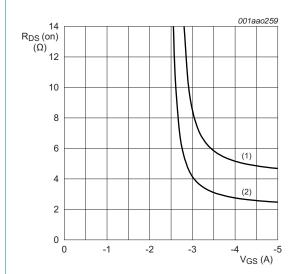
 $T_{j} = 25 \, ^{\circ}\text{C}; \, V_{DS} = -5 \, \text{V}$ 

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage



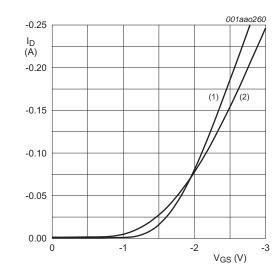
 $I_D = -200 \text{ mA}$ 

(1)  $T_i = 150 \, ^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}C$ 

Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values

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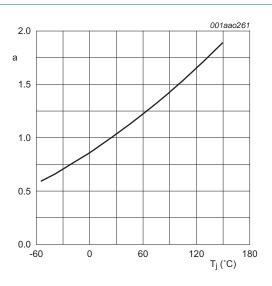


 $V_{DS} > I_D \times R_{DSon}$ 

(1) 
$$T_i = 25 \, ^{\circ}C$$

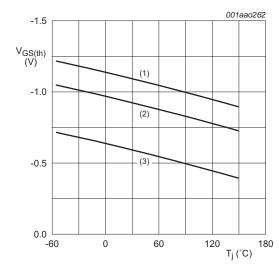
(2) 
$$T_j = 150 \, ^{\circ}\text{C}$$

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

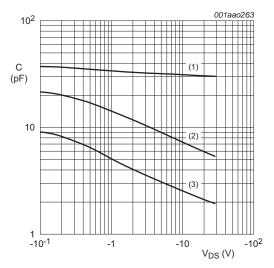
Fig 11. Normalized drain-source on-state resistance as a function of junction temperature; typical values



 $I_D$  = -0.25 mA;  $V_{DS}$  =  $V_{GS}$ 

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of junction temperature



 $f = 1 MHz; V_{GS} = 0 V$ 

(1)C<sub>iss</sub>

(2)C<sub>oss</sub>

(3)C<sub>rss</sub>

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

#### 30 V, 230 mA P-channel Trench MOSFET

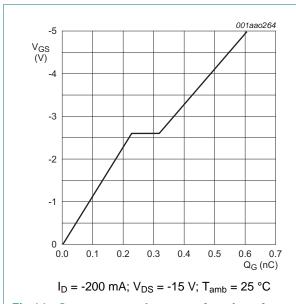


Fig 14. Gate-source voltage as a function of gate charge; typical values

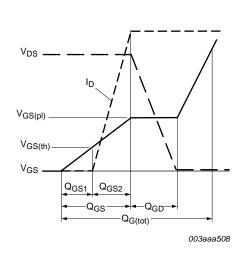
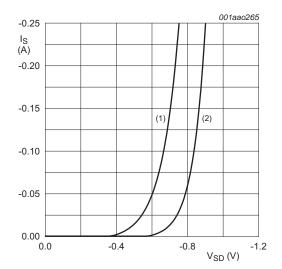


Fig 15. Gate charge waveform definitions



 $V_{GS} = 0 V$ 

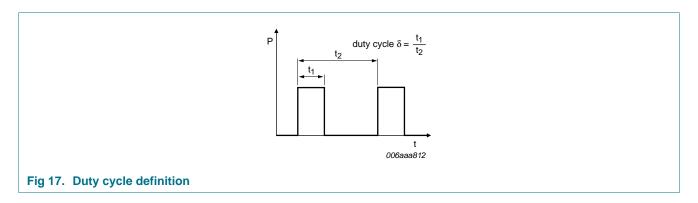
(1)  $T_i = 150 \, ^{\circ}\text{C}$ 

(2)  $T_j = 25 \, ^{\circ}C$ 

Fig 16. Source current as a function of source-drain voltage; typical values

30 V, 230 mA P-channel Trench MOSFET

## 8. Test information



## 8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

## 9. Package outline

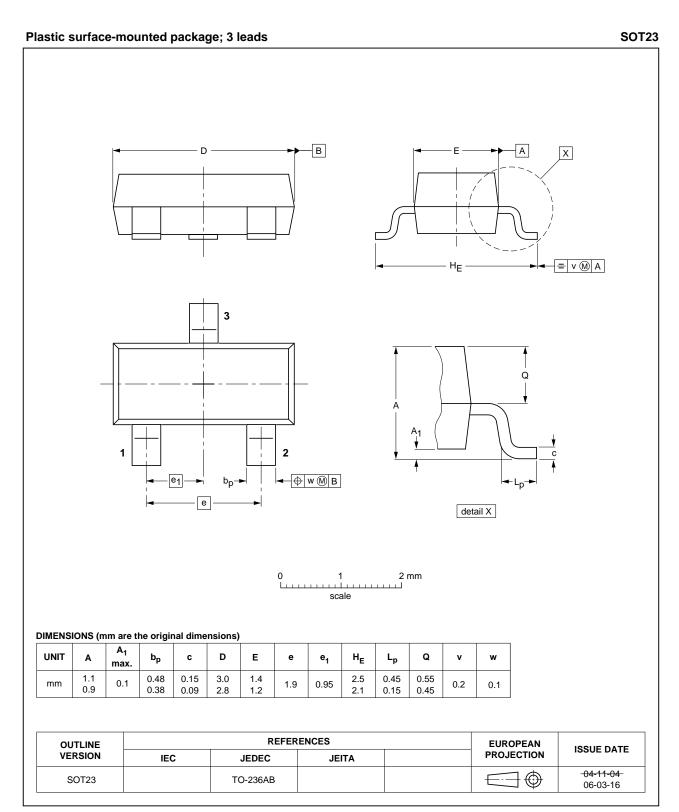
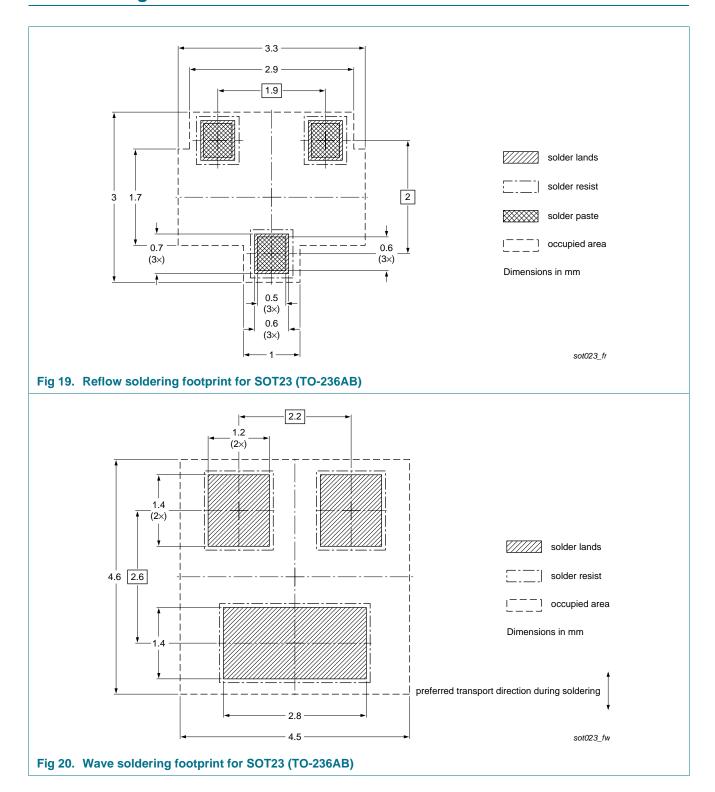


Fig 18. Package outline SOT23 (TO-236AB)

30 V, 230 mA P-channel Trench MOSFET

## 10. Soldering



## 30 V, 230 mA P-channel Trench MOSFET

## 11. Revision history

#### Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3008PBK v.1	20110801	Product data sheet	-	-

#### 30 V, 230 mA P-channel Trench MOSFET

## 12. Legal information

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Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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